TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSIII)

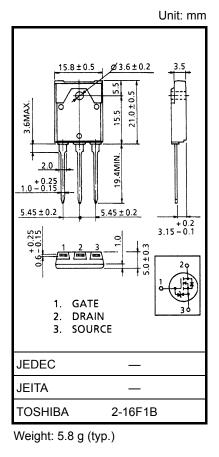
2SK3017

DC–DC Converter, Relay Drive and Motor Drive Applications

- Low drain-source ON resistance $: RDS (ON) = 1.05 \Omega (typ.)$
- High forward transfer admittance $|Y_{fs}| = 7.0 \text{ S (typ.)}$
 - Low leakage current $I_{DSS} = 100 \ \mu A \ (max) \ (V_{DS} = 720 \ V)$
- Enhancement mode : $V_{th} = 2.0 \sim 4.0 \text{ V} (V_{DS} = 10 \text{ V}, \text{ ID} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V _{DSS}	900	V
Drain-gate voltage (R _{GS} = 20 kΩ)		V _{DGR}	900	V
Gate-source voltage	_	V _{GSS}	±30	V
Drain current	DC (Note 1)	۱ _D	8.5	А
	Pulse (Note 1)	I _{DP}	25.5	А
Drain power dissipation (Tc = 25°C)		PD	90	W
Single pulse avalanche energy (Note 2)		E _{AS}	966	mJ
Avalanche current		I _{AR}	8.5	А
Repetitive avalanche energy (Note 3)		E _{AR}	9	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C



Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and

Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch−c)}	1.39	°C / W
Thermal resistance, channel to ambient	R _{th (ch−a)}	41.6	°C / W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 90 V, T_{ch} = 25°C (initial), L = 24.5 mH, R_G = 25 Ω , I_{AR} = 8.5 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.

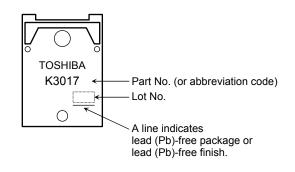
Electrical Characteristics (Ta = 25°C)

Charao	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V_{GS} = ±30 V, V_{DS} = 0 V	_	_	±10	μA
Gate-source bro	eakdown voltage	V _(BR) GSS	I _G = ±10 μA, V _{DS} = 0 V	±30	_	_	V
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 720 V, V _{GS} = 0 V	_	_	100	μA
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	900	_	_	V
Gate threshold v	voltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 4 A		1.05	1.25	Ω
Forward transfe	r admittance	Y _{fs}	V _{DS} = 15 V, I _D = 4 A	3.5	7.0	_	S
Input capacitant	ce	C _{iss}			2150	_	pF
Reverse transfe	r capacitance	C _{rss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	_	35	_	
Output capacita	Output capacitance		C _{oss}	_	220	_	1
Switching time Fall time	Rise time	tr	$V_{GS} \stackrel{10 \text{ V}}{}_{O \text{ V}} \stackrel{I_{D} = 4 \text{ A}}{\underset{C \neq}{}_{O \text{ V}}} \stackrel{V_{OUT}}{\underset{C \neq}{}_{O \text{ V}}} \stackrel{I_{D} = 4 \text{ A}}{\underset{C \neq}{}_{O \text{ V}}} \stackrel{V_{OUT}}{\underset{R_{L} =}{}_{O \text{ V}}}$	_	25	_	
	Turn-on time	t _{on}		_	60	_	20
	Fall time	t _f	$\begin{array}{c c} & \overrightarrow{V} & \overrightarrow{V} \\ \overrightarrow{V} & \overrightarrow{V} & \overrightarrow{V} \\ & & & V_{DD} \\ \end{array} \doteq 400 V$	_	25	_	ns
	Turn-off time	t _{off}	Duty $\leq 1\%$, t _w = 10 µs	_	120		
Total gate charge (Gate-source plus gate-drain) Gate-source charge		Qg		_	70	_	
		Q _{gs}	V _{DD} ≈ 400 V, V _{GS} = 10 V, I _D = 8 A	_	37	_	nC
Gate-drain ("mil	ller") charge	Q _{gd}	gd		33	_	

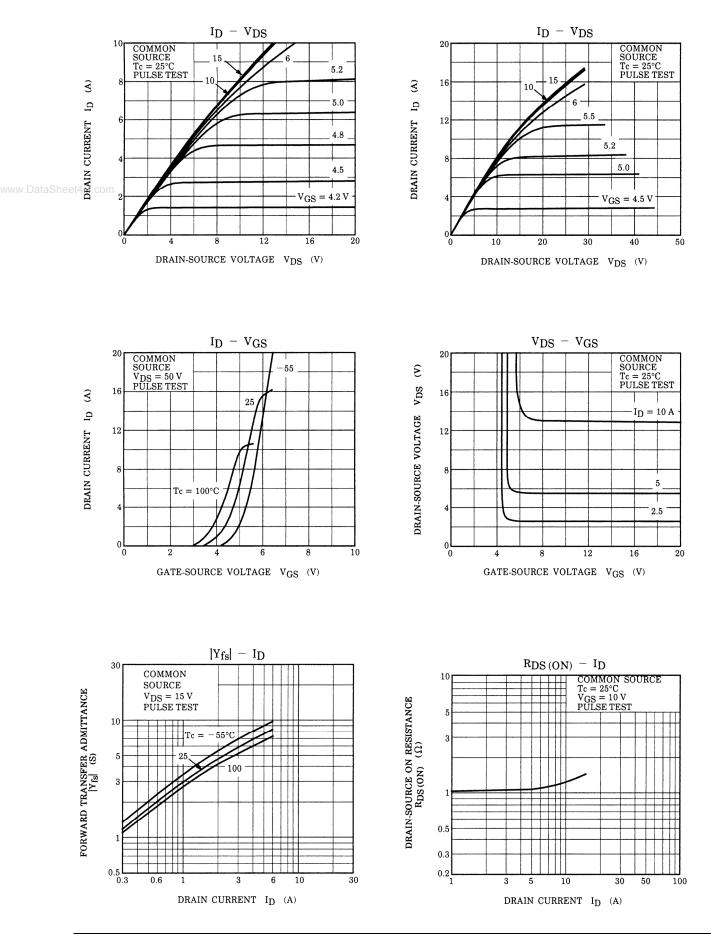
Source–Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	8.5	А
Pulse drain reverse current (Note 1)	I _{DRP}	—			25.5	А
Forward voltage (diode)	V _{DSF}	I _{DR} = 8.5 A, V _{GS} = 0 V	_	_	-1.9	V
Reverse recovery time	t _{rr}	I _{DR} = 8.5 A, V _{GS} = 0 V	_	1300	_	ns
Reverse recovery charge	Qrr	dI _{DR} / dt = 100 Å / µs		14.5		μC

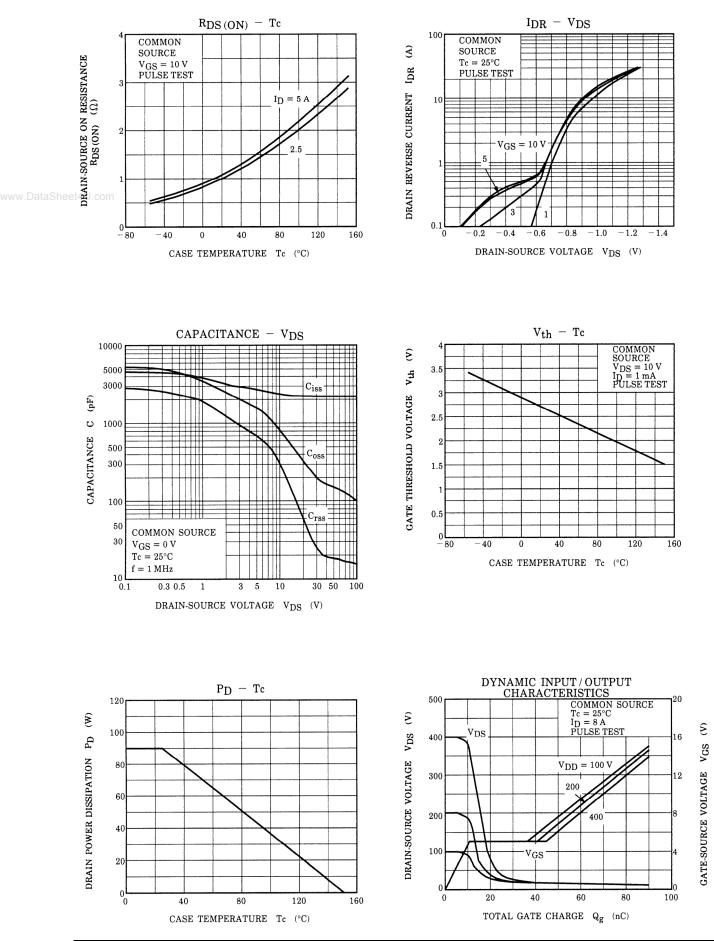
Marking



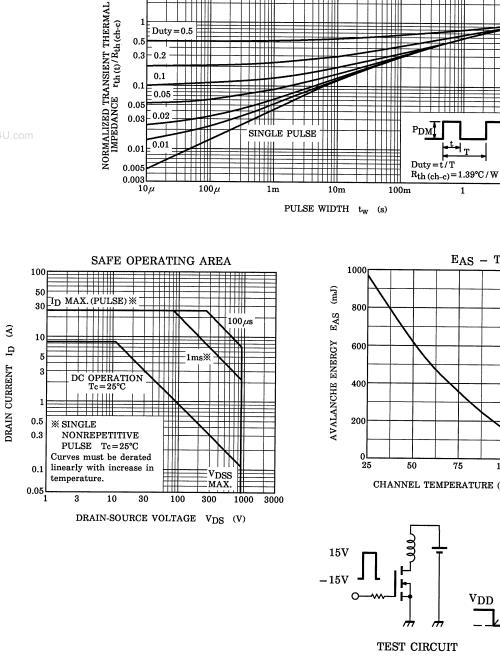
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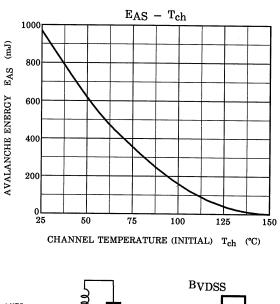


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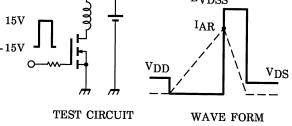


 $r_{th} - t_w$

Duty = 0.5



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$$\begin{aligned} \mathrm{R}_{\mathrm{G}} &= 25 \ \Omega \\ \mathrm{V}_{\mathrm{DD}} &= 90 \ \mathrm{V}, \ \mathrm{L} &= 24.5 \ \mathrm{mH} \end{aligned} \qquad \mathrm{E}_{\mathrm{AS}} &= \frac{1}{2} \cdot \mathrm{L} \cdot \mathrm{I}^2 \cdot \left(\frac{\mathrm{B} \mathrm{V}\mathrm{D}\mathrm{SS}}{\mathrm{B} \mathrm{V}\mathrm{D}\mathrm{SS} - \mathrm{V}\mathrm{D}\mathrm{D}} \right) \end{aligned}$$

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